

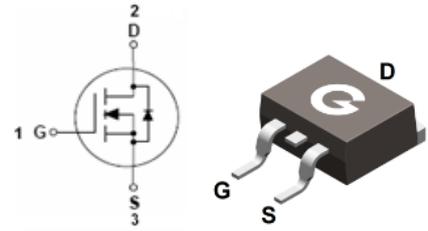
### Features

- Proprietary new trench technology
- Fast recovery body diode
- Pb-free lead plating; RoHS compliant

HF

### Mechanical Data

- Case: TO-263
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208



TO-263

### Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL035N04HB	TO-263	50 pcs / Tube & 800 pcs / Tape & Reel	035N04HB

### Maximum Ratings (@ T<sub>A</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	40	V
Gate-to-Source Voltage	V <sub>GSS</sub>	±20	V
Continuous Drain Current (T <sub>C</sub> = 25°C, Silicon limited)	I <sub>D</sub>	200	A
Continuous Drain Current (T <sub>C</sub> = 100°C, Silicon limited)		125	A
Continuous Drain Current (T <sub>C</sub> = 25°C, Package limited)		80	A
Continuous Drain Current (T <sub>A</sub> = 25°C, R <sub>θJA</sub> =43°C/W )		21	A
Pulsed Drain Current*1	I <sub>DM</sub>	690	A
Single Pulse Avalanche Energy *4	E <sub>AS</sub>	600	mJ

### Thermal Characteristics

Parameter	Symbol	Value	Unit
Power Dissipation (T <sub>C</sub> = 25°C)	P <sub>D</sub>	250	W
Thermal Resistance Junction-to-Air *2	R <sub>θJA</sub>	62	°C/W
Thermal Resistance Junction-to-Air *6	R <sub>θJA</sub>	43	°C/W
Thermal Resistance Junction-to-Case	R <sub>θJC</sub>	0.9	°C/W
Operating Junction Temperature Range	T <sub>J</sub>	-55 ~ +150	°C
Storage Temperature Range	T <sub>STG</sub>	-55 ~ +150	°C

### Electrical Characteristics (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 1mA$	40	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 40V, V_{GS} = 0V$	-	-	1	$\mu A$
$I_{GSS}$	Gate-Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
$R_{DS(ON)}$	Static Drain-Source On-resistance <sup>*3</sup>	$V_{GS} = 10V, I_D = 80A$	-	2.4	3.5	m $\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3	4	V
$R_G$	Gate resistance	$f = 1MHz$	-	2.6	-	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{ISS}$	Input Capacitance	$V_{GS} = 0V$	-	5800	-	pF
$C_{OSS}$	Output Capacitance	$V_{DS} = 25V$	-	680	-	
$C_{RSS}$	Reverse Transfer Capacitance	$f = 1.0MHz$	-	500	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD} = 20V$	-	21	-	ns
$t_r$	Turn-on Rise Time	$V_{GS} = 10V$	-	22	-	
$t_{d(OFF)}$	Turn-Off Delay Time	$R_G = 2.5\Omega$	-	53	-	
$t_f$	Turn-Off Fall Time	$I_D = 80A$	-	21	-	
<b>Gate charge characteristics</b>						
$Q_G$	Total Gate-Charge	$V_{DD} = 20V$	-	95	-	nC
$Q_{GS}$	Gate to Source Charge	$I_D = 80A$	-	40	-	
$Q_{GD}$	Gate to Drain (Miller) Charge	$V_{GS} = 10V$	-	20	-	
<b>Source-Drain Diode Characteristics</b>						
$V_{SD}$	Diode Forward Voltage <sup>*3</sup>	$I_{SD} = 80A, V_{GS} = 0V$	-	1	1.2	V
$t_{rr}$	Reverse recovery time	$V_R = 30V, I_F = 40A,$ $di/dt = 100A/\mu s,$	-	52	-	ns
$Q_{rr}$	Reverse recovery charge		-	53	-	nC
$I_{RRM}$	Reverse recovery current		-	1.8	-	A

Notes:

- $t_p = 10\mu s$ , duty cycle = 1% .
- The data tested by surface mounted on suggest footprint
- The data tested by pulsed, pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$
- The  $E_{AS}$  data shows Max. ratings. The test condition is  $V_{DD} = 30V, V_{GS} = 10V, L = 1mH, I_{AS} = 35A$
- The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation
- Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1-inch square copper plate

Ratings and Characteristics Curves (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)

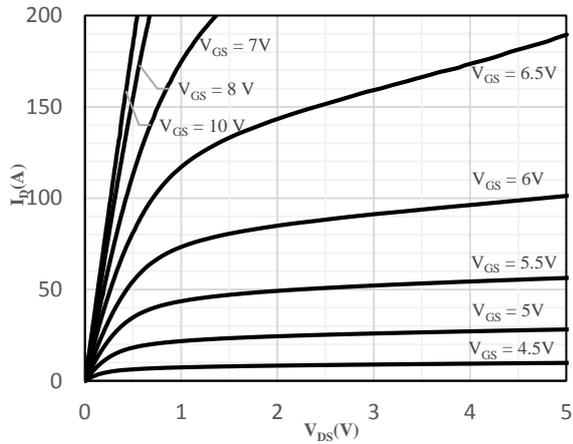


Fig 1 Typical Output Characteristics

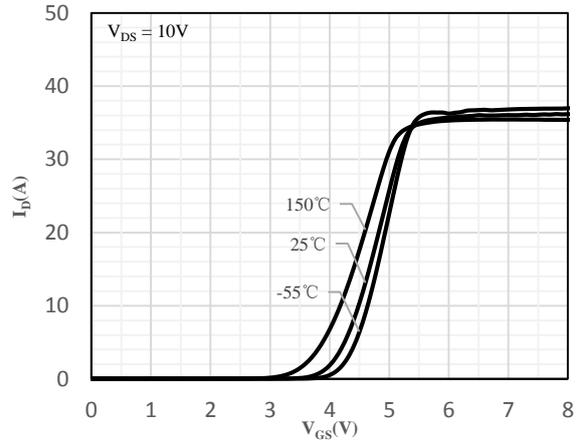


Fig 2 Transfer Characteristics

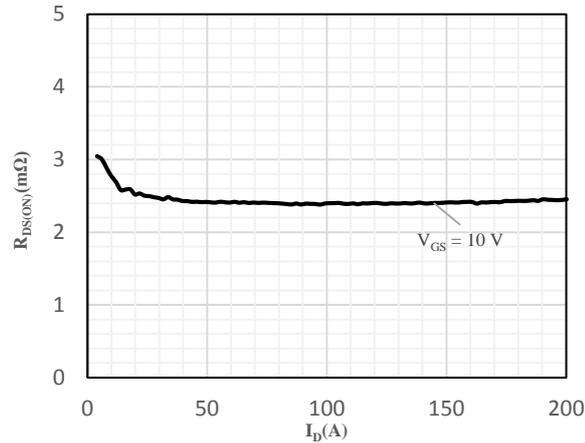


Fig 3 Drain-source on resistance

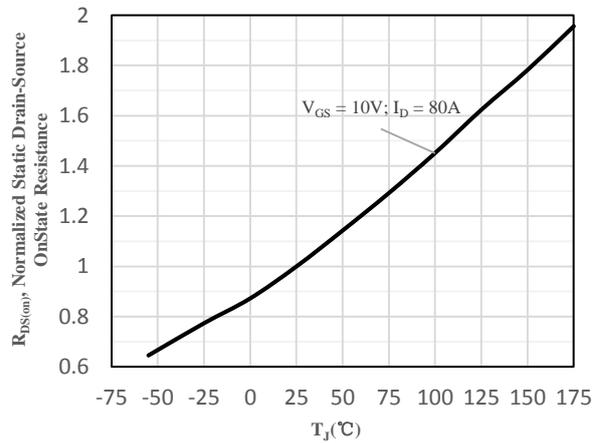


Fig 4 On-Resistance vs. Junction Temperature

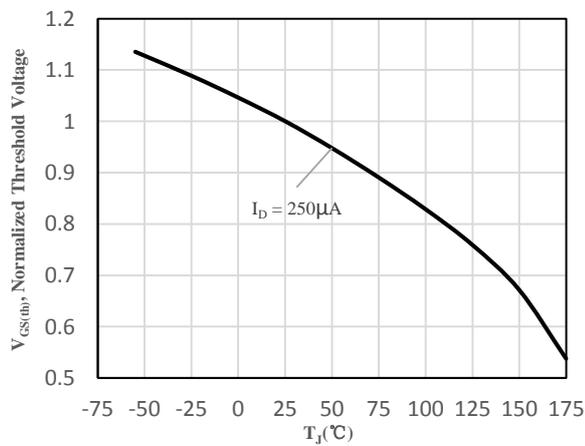


Fig 5 Gate Voltage vs. Junction Temp

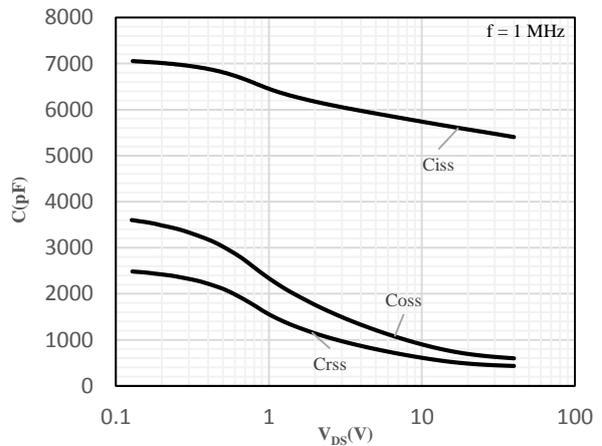


Fig 6 Capacitance Characteristics

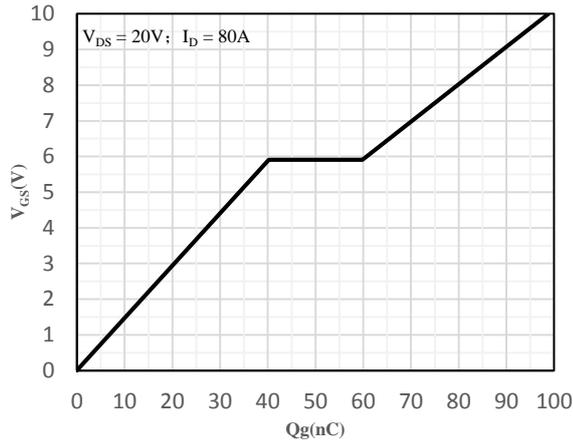


Fig 7 Gate-Charge Characteristics

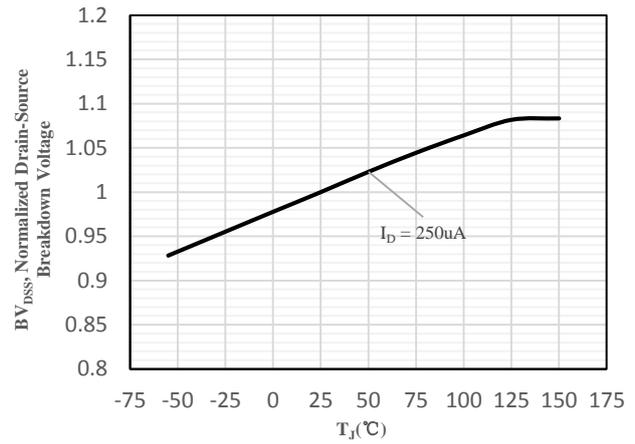


Fig 8 Drain-Source breakdown voltage

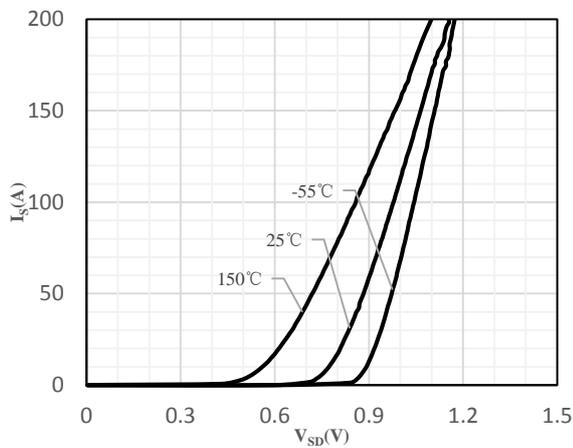


Fig 9 Forward characteristics of reverse diode

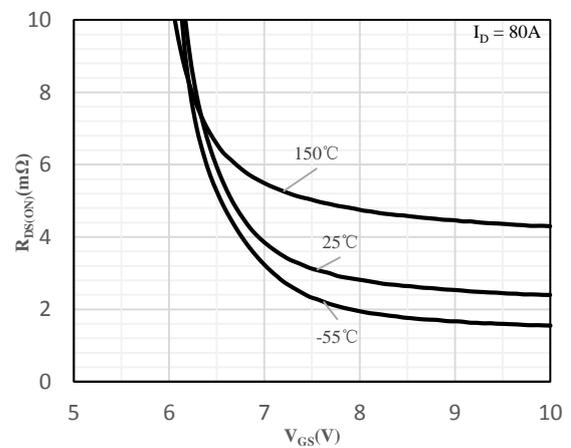


Fig 10 Gate-Source On Resistance

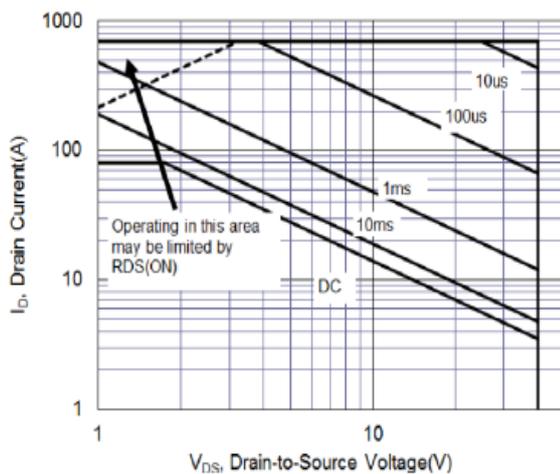
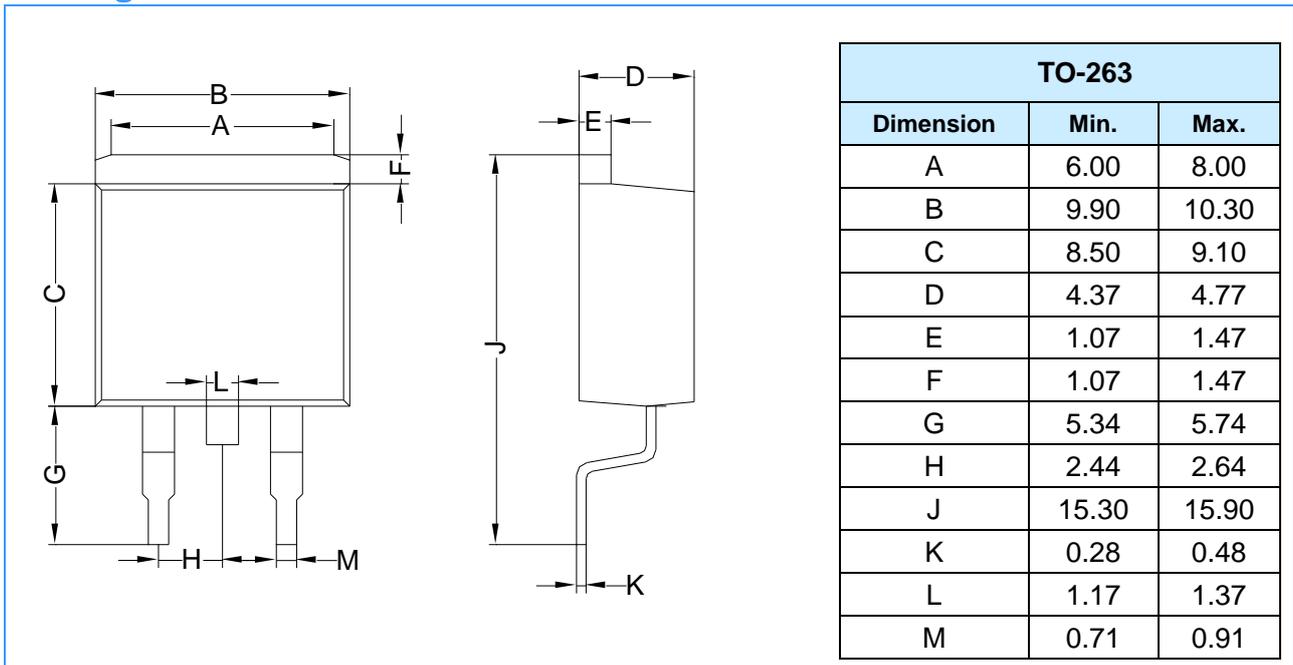
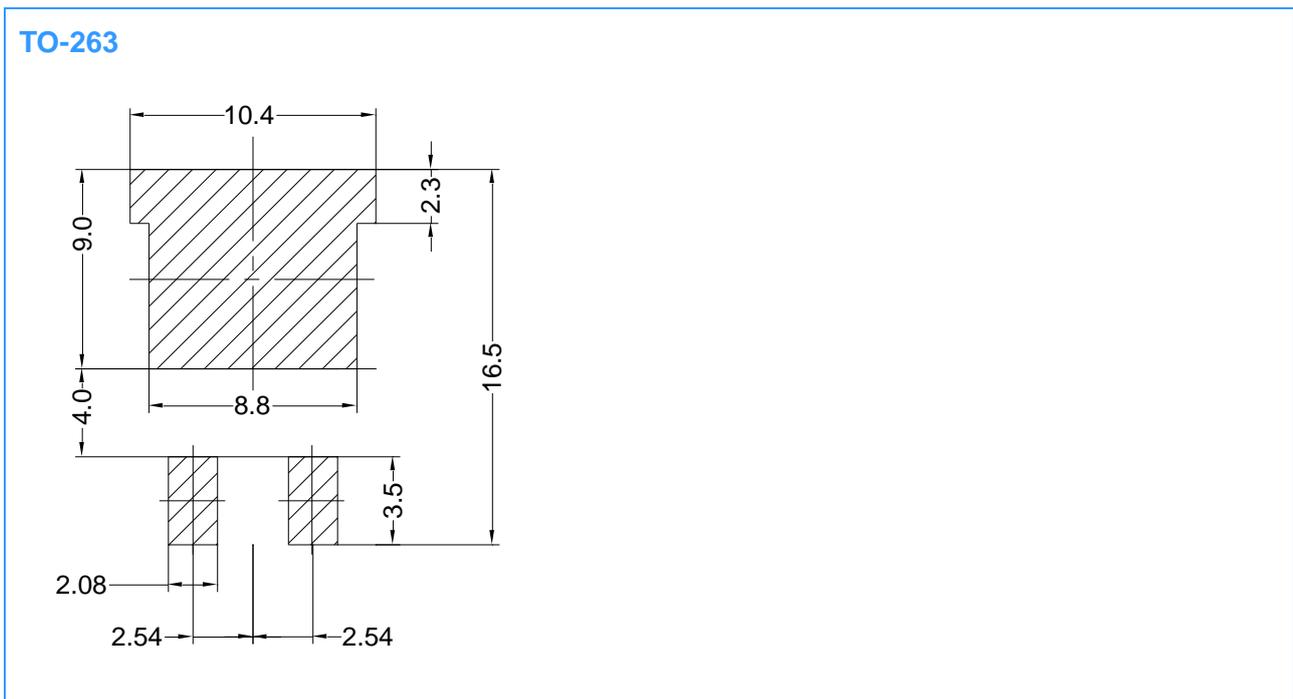


Fig 11 Safe operating area

**Package Outline Dimensions** (Unit: mm)



**Mounting Pad Layout** (Unit: mm)



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